

OptiMOS™-T2 Power-Transistor

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Product Summary

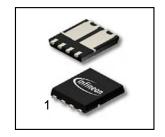
V _{DS}	40	V
R _{DS(on),max} ⁴⁾	8.6	mΩ
I _D	20	Α

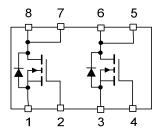
Features

- Dual N-channel Normal Level Enhancement mode
- AEC Q101 qualified
- MSL1 up to 260°C peak reflow
- 175°C operating temperature
- Green Product (RoHS compliant)
- 100% Avalanche tested
- Feasible for automatic optical inspection (AOI)

Туре	Package	Marking
IPG20N04S4-09A	PG-TDSON-8	4N0409

PG-TDSON-8





Maximum ratings, at T_j =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current one channel active	I _D	T _C =25 °C, V _{GS} =10 V ¹⁾	20	А
		T _C =100 °C, V _{GS} =10 V ²⁾	20	
Pulsed drain current ²⁾ one channel active	I _{D,pulse}	-	80	
Avalanche energy, single pulse ^{2, 4)}	E _{AS}	/ _D =10A	145	mJ
Avalanche current, single pulse ⁴⁾	IAS	-	15	А
Gate source voltage	V_{GS}	-	±20	V
Power dissipation one channel active	P_{tot}	T _C =25 °C	54	W
Operating and storage temperature	$T_{\rm j},T_{\rm stg}$	-	-55 +175	°C



Parameter	Symbol	Conditions	Values		Unit	
			min.	typ.	max.	
Thermal characteristics ²⁾						
Thermal resistance, junction - case	R_{thJC}	-	-	-	2.8	K/W
SMD version, device on PCB	R_{thJA}	minimal footprint	-	100	-	
		6 cm ² cooling area ³⁾	-	60	-	1

Electrical characteristics, at T_j =25 °C, unless otherwise specified

Static characteristics

Drain-source breakdown voltage	V _{(BR)DSS}	$V_{\rm GS}$ =0 V, $I_{\rm D}$ = 1 mA	40	-	-	V
Gate threshold voltage	$V_{\rm GS(th)}$	$V_{\rm DS} = V_{\rm GS}$, $I_{\rm D} = 22\mu \rm A$	2.0	3.0	4.0	
Zero gate voltage drain current ⁴⁾	I _{DSS}	V _{DS} =40 V, V _{GS} =0 V, T _j =25 °C	-	0.01	1	μΑ
		$V_{\rm DS}$ =18 V, $V_{\rm GS}$ =0 V, $T_{\rm j}$ =85 °C ²⁾	ı	1	100	
Gate-source leakage current ⁴⁾	I _{GSS}	$V_{\rm GS}$ =20 V, $V_{\rm DS}$ =0 V	ı	ı	100	nA
Drain-source on-state resistance ⁴⁾	R _{DS(on)}	V _{GS} =10 V, I _D =17 A	-	7.9	8.6	mΩ



Parameter	Symbol	Symbol Conditions	Values			Unit
			min.	typ.	max.	
Dynamic characteristics ²⁾						
Input capacitance ⁴⁾	C _{iss}		-	1730	2250	pF
Output capacitance ⁴⁾	Coss	V _{GS} =0 V, V _{DS} =25 V, f=1 MHz	-	440	570	
Reverse transfer capacitance ⁴⁾	C _{rss}		-	13	30	
Turn-on delay time	$t_{d(on)}$		-	12	-	ns
Rise time	t _r	V _{DD} =20 V, V _{GS} =10 V,	-	3	-	
Turn-off delay time	$t_{d(off)}$	I_{D} =20 A, R_{G} =11 Ω	-	15	-	
Fall time	t _f]	-	10	-	
Gate Charge Characteristics ^{2, 4)}				-		_
Gate to source charge	Q _{gs}		-	9.1	12	nC
Gate to drain charge	Q _{gd}	V _{DD} =32 V, I _D =20 A,	-	2.9	6.7	
Gate charge total	Qg	V _{GS} =0 to 10 V	-	21.7	28	
Gate plateau voltage	V _{plateau}		-	5.3	-	V
Reverse Diode	•			-		-
Diode continous forward current ²⁾ one channel active	Is	− T _C =25 °C	-	-	20	A
Diode pulse current ²⁾ one channel active	I _{S,pulse}		-	-	80	
Diode forward voltage	V _{SD}	V _{GS} =0 V, I _F =17 A, T _j =25 °C	-	0.9	1.3	V
Reverse recovery time ²⁾	t _{rr}	V_{R} =20 V, I_{F} = I_{S} , di_{F}/dt =100 A/ μ s	-	34	-	ns
Reverse recovery charge ^{2, 4)}	Q _{rr}		-	30	-	nC

 $^{^{1)}}$ Current is limited by bondwire; with an $R_{\rm thJC}$ =2.8 K/W the chip is able to carry 61A at 25°C.

²⁾ Specified by design. Not subject to production test.

 $^{^{3)}}$ Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm² (one layer, 70 μm thick) copper area for drain connection. PCB is vertical in still air.

⁴⁾ Per channel

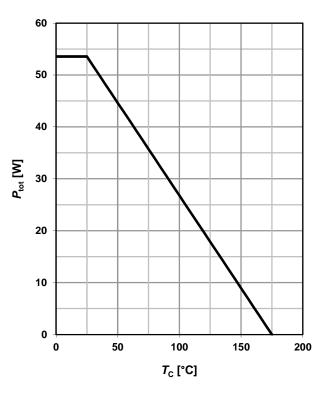


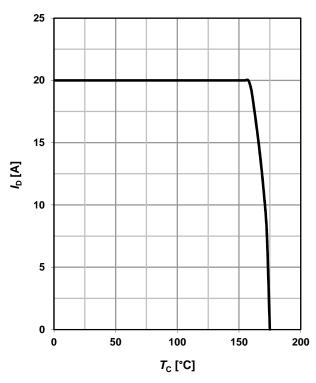
1 Power dissipation

 $P_{\text{tot}} = f(T_{\text{C}}); V_{\text{GS}} = 10\text{V}; \text{ one channel active}$

2 Drain current

 $I_D = f(T_C)$; $V_{GS} = 10 \text{ V}$; one channel active





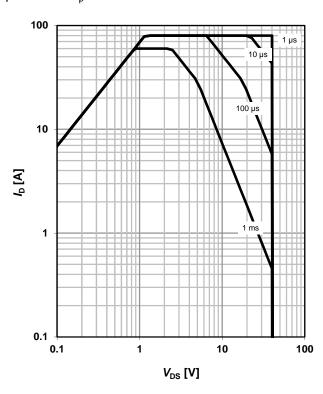
3 Safe operating area

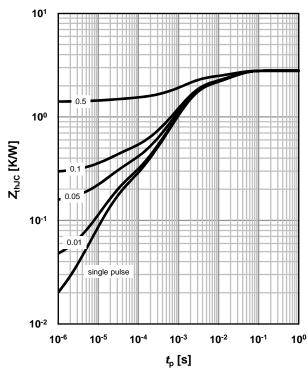
 $I_{\rm D} = f(V_{\rm DS}); \ T_{\rm C} = 25 {\rm ^{\circ}C}; \ D = 0;$ one channel active parameter: $t_{\rm p}$

4 Max. transient thermal impedance

 $Z_{thJC} = f(t_p)$

parameter: $D=t_p/T$







5 Typ. output characteristics⁴⁾

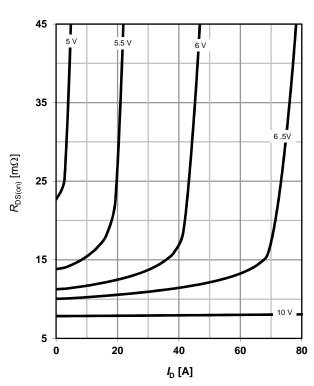
 $I_{D} = f(V_{DS}); T_{j} = 25 \text{ °C}$

parameter: V_{GS}

6 Typ. drain-source on-state resistance⁴⁾

 $R_{DS(on)} = f(I_D); T_j = 25 \text{ °C}$

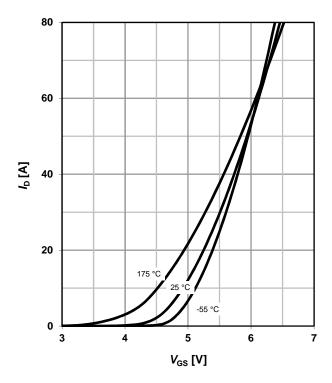
parameter: $V_{\rm GS}$



7 Typ. transfer characteristics⁴⁾

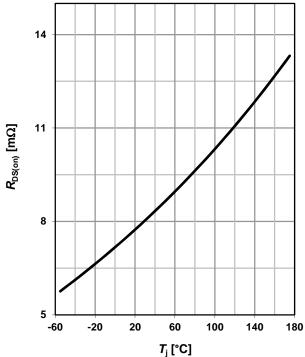
 $I_D = f(V_{GS}); V_{DS} = 6V$

parameter: T_j



8 Typ. drain-source on-state resistance⁴⁾

$$R_{DS(on)} = f(T_j); I_D = 17 \text{ A}; V_{GS} = 10 \text{ V}$$





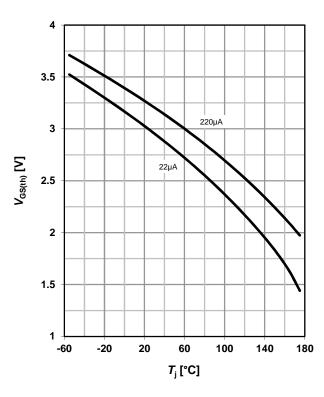
9 Typ. gate threshold voltage

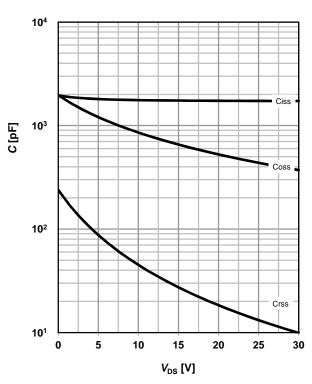
 $V_{GS(th)} = f(T_j); V_{GS} = V_{DS}$

parameter: I_D

10 Typ. Capacitances⁴⁾

 $C = f(V_{DS}); V_{GS} = 0 V; f = 1 MHz$





11 Typical forward diode characteristicis⁴⁾

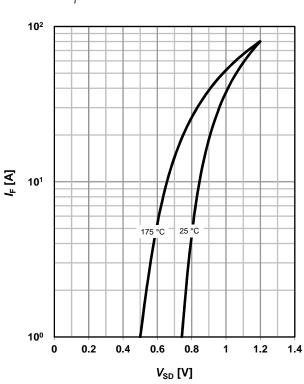
 $IF = f(V_{SD})$

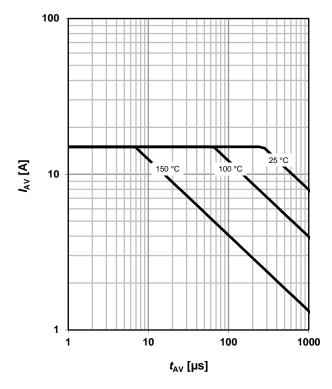
parameter: $T_{\rm j}$

12 Avalanche characteristics⁴⁾

 $I_{AS} = f(t_{AV})$

parameter: T_{j(start)}







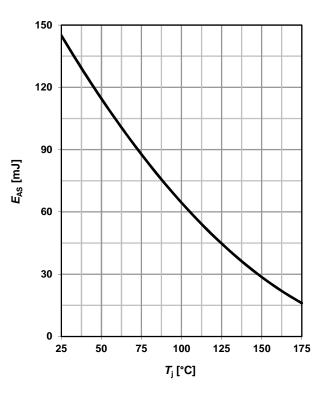
13 Avalanche energy⁴⁾

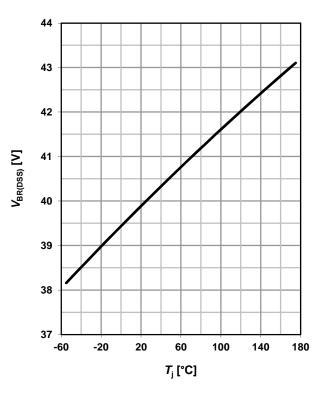
 $E_{AS} = f(T_i)$

parameter: I_D

14 Drain-source breakdown voltage

 $V_{BR(DSS)} = f(T_i); I_D = 1 \text{ mA}$

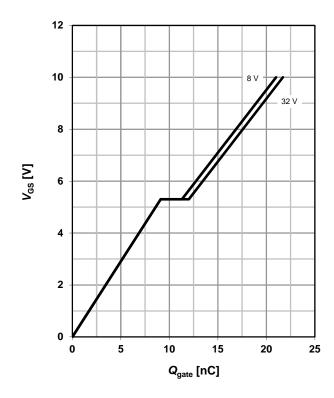




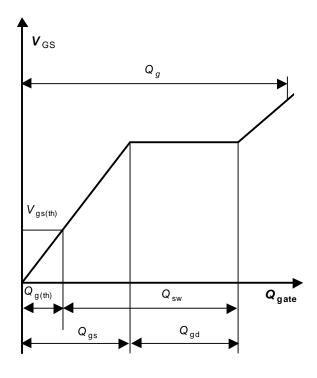
15 Typ. gate charge⁴⁾

 $V_{GS} = f(Q_{gate}); I_D = 20 A pulsed$

parameter: $V_{\rm DD}$



16 Gate charge waveforms





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Revision History

Version	Date	Changes		
Revision 1.0	03.05.2015	Data Sheet revision 1.0		
Revision 1.01	31.05.2024 Package naming updated			

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